

L Number	Hits	Search Text	DB	Time stamp
1	12135	"209/571" "209/573" "324/158.1" "324/759" "324/764" "324/765" "700/96" "700/108" "700/109" "700/121"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 14:46
2	45	((chip circuit electronic) near3 test\$3) same ((stor\$3 sav\$3) and (test result) and (flag data) and (identification near3 code))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 14:47
4	59	((chip circuit electronic) near3 test\$3) same ((stor\$3 sav\$3) and (test result) and (identification near3 code)) )	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 14:50
3	20	("209/571" "209/573" "324/158.1" "324/759" "324/764" "324/765" "700/96" "700/108" "700/109" "700/121") and (((chip circuit electronic) near3 test\$3) same ((stor\$3 sav\$3) and (test result) and (flag data) and (identification near3 code)) )	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 14:58
5	3	("5742173"   "5805472"   "6097204").PN.	USPAT	2003/09/05 14:51
6	12	("4869636"   "5148100"   "5184068"   "5227717"   "5290134"   "5307011"   "5313156"   "5347463"   "5625287"   "5635832"   "5652523"   "5654204").PN.	USPAT	2003/09/05 14:52
7	39	(((((chip circuit electronic) near3 test\$3) same ((stor\$3 sav\$3) and (test result) and (identification near3 code)) )) not (("209/571" "209/573" "324/158.1" "324/759" "324/764" "324/765" "700/96" "700/108" "700/109" "700/121") and (((chip circuit electronic) near3 test\$3) same ((stor\$3 sav\$3) and (test result) and (flag data) and (identification near3 code)) ))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 15:01
-	515	"209/573" "209.574"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 16:40
-	7	"6350959"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 18:05
-	4	"6373011"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 18:06
-	55	"5927512"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 18:06
-	0	6373011.URPN.	USPAT	2003/09/03 18:15
-	12135	"209/571" "209/573" "324/158.1" "324/759" "324/764" "324/765" "700/96" "700/108" "700/109" "700/121"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 14:46
-	6216	((chip circuit electronic) near3 test\$3) same ((stor\$3 sav\$3) and (test result) and (flag data))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 17:06

-	575	("209/571" "209/573" "324/158.1" "324/759" "324/764" "324/765" "700/96" "700/108" "700/109" "700/121") and (((chip circuit electronic) near3 test\$3) same ((stor\$3 sav\$3) and (test result) and (flag data)) )	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 17:06
-	45	((chip circuit electronic) near3 test\$3) same ((stor\$3 sav\$3) and (test result) and (flag data) and (identification near3 code))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 14:46
-	20	("209/571" "209/573" "324/158.1" "324/759" "324/764" "324/765" "700/96" "700/108" "700/109" "700/121") and (((chip circuit electronic) near3 test\$3) same ((stor\$3 sav\$3) and (test result) and (flag data) and (identification near3 code)) )	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 14:46